



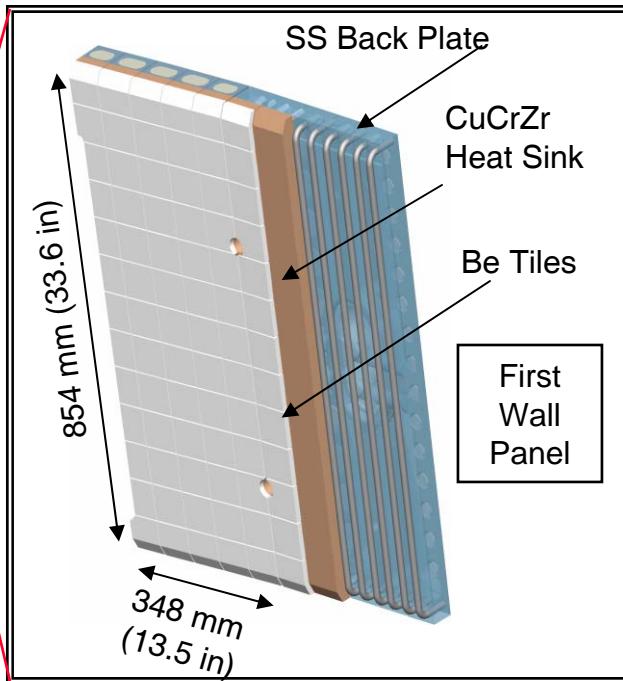
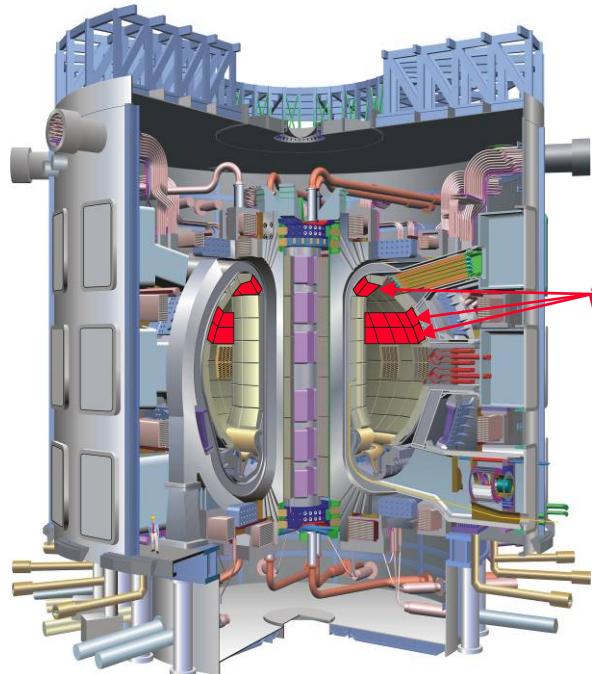
Diffusion Bonding of ITER First Wall Structures

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ITER – Joint International Effort on Fusion Energy



Party Teams

- China
- EU
- India
- Japan
- Korea
- Russian Fed.
- USA

- Goal: Demonstrate fusion can be used to generate electrical power
 - Generate 500 MW of power (10x input power)
 - First fusion reactor to actually produce power
- Hardware mostly provide “in-kind” by the party teams
- First wall faces plasma and current design uses Be armor tiles
- Goal is to bond beryllium to copper alloy substrate



Requirements and Limitations

- Final structure requires two bonds
 - SS to Cu alloy
 - Cu alloy to Be
- Copper alloy is age hardenable
 - C18150 - 0.1% Zr, 1.0% Cr, 98.9% Cu
 - Solutionize ~ 980 °C and H₂O quench
 - Peak aging ~ 475 °C
 - Requires solutionizing and aging!
 - CuCrZr YS/UTS(MPa) 175/280@RT, 150/220@250C
- Environment necessitates robust bonds
 - Components be intimately bonded to transfer heat
 - Tens of thousands of thermal cycles
 - Occasional very rapid high heat loads
 - 60 MJ/m² in 0.5 sec VDE load

Be – S65C

CuCrZr

316L Stainless



Requirements and Limitations Cont.

- **End result is many limitations**
 - Melting point must be high – no Al
 - Can't add appreciable thickness – compliance layers?
 - No materials that activate – Ag » Cd, Au » Hg
 - Copper alloy needs to be heat treated
 - Sundry engineering issues
- **Most obvious (logical?) approach**
 1. Join copper alloy to stainless base
 2. Solutionize copper alloy
 3. Develop a low temperature bonding process that joins and ages the copper at the same time
 - Aging characteristics of CuCrZr require < 600°C

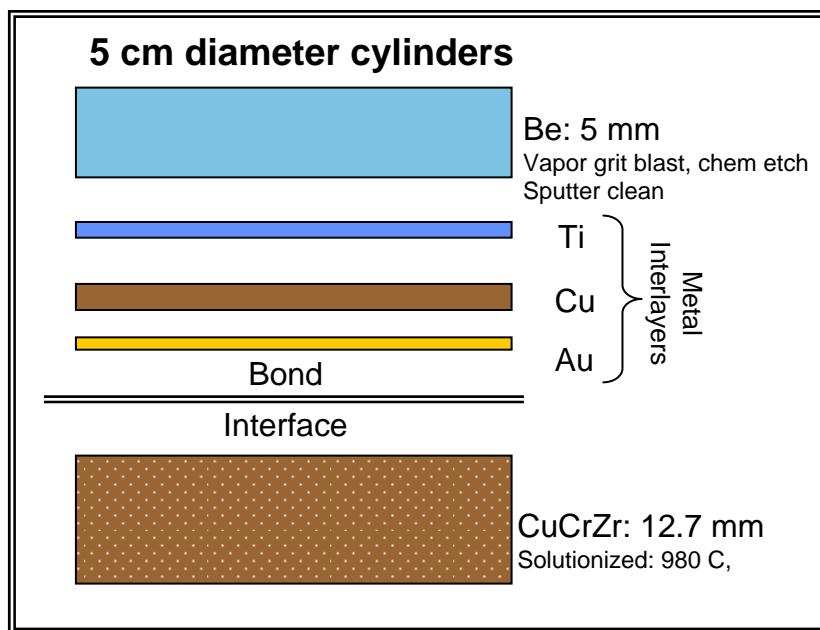
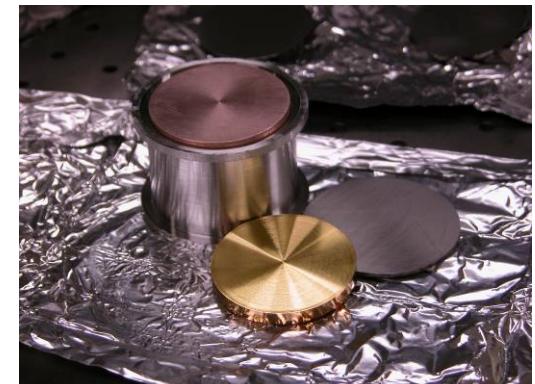
} Combine?

Traditional Joining Techniques Generally Not Acceptable



Approach

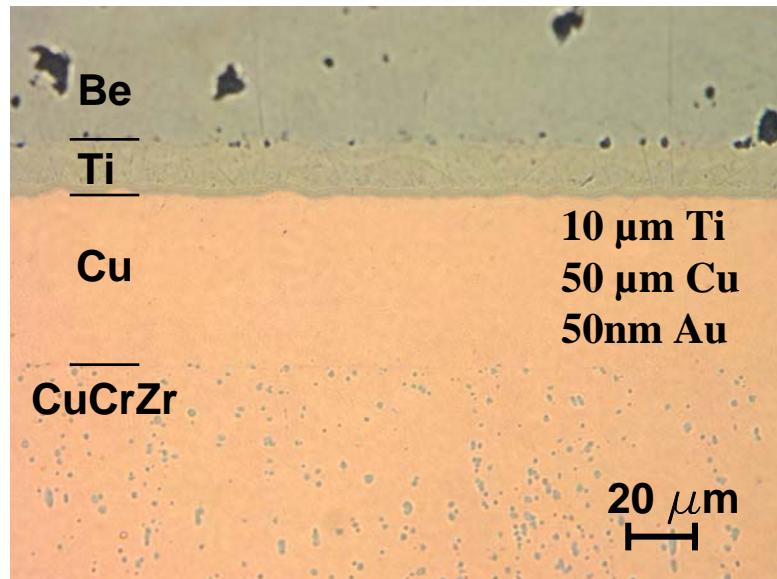
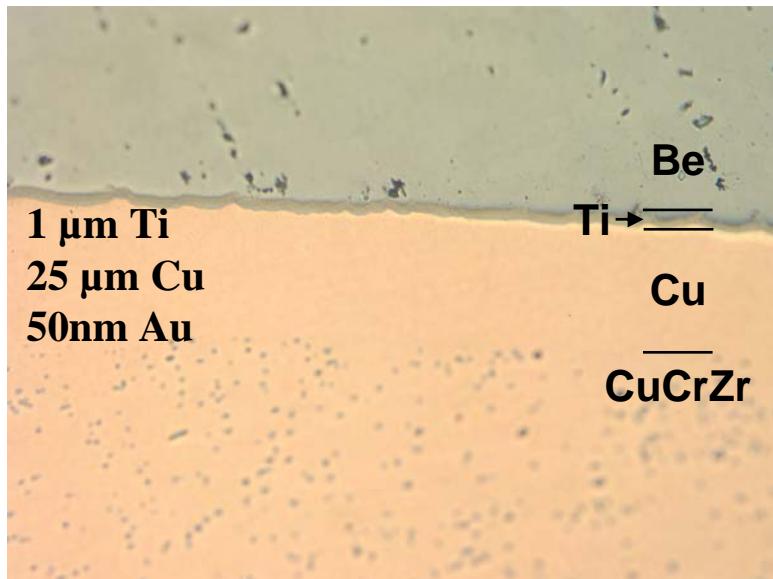
- Metallization layers – physical vapor deposition (PVD)
 - Promote adhesion,
 - Provide compliance,
 - Inhibit undesirable intermetallics, e.g. Be-Cu
 - Provide an oxidation barrier
- Diffusion bond by hot isostatic pressing (HIP)
 - 100 MPa, 580°C for 2 hours



Index #	Ti Diffusion Barrier (μm)	Cu Compliant Layer (μm)	Au Oxidation Barrier (nm)
1	1	25	50
2	10	25	50
3	1	50	50
4	10	50	50



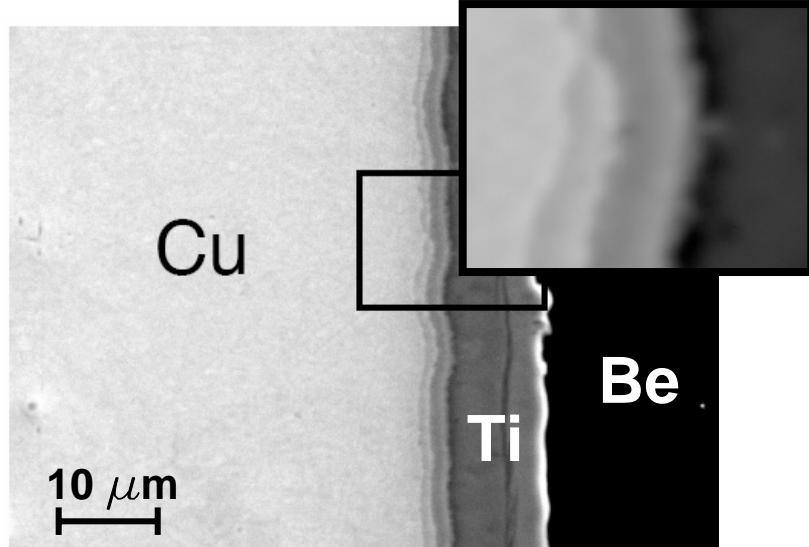
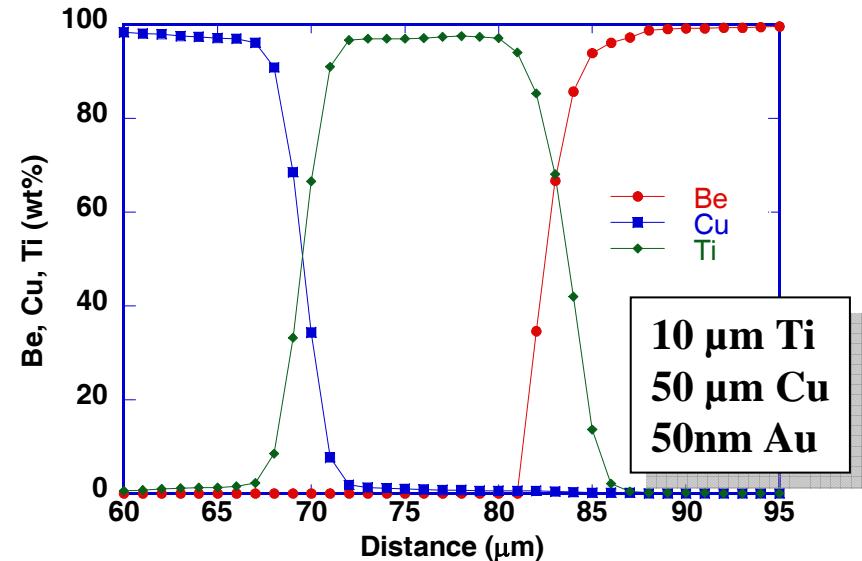
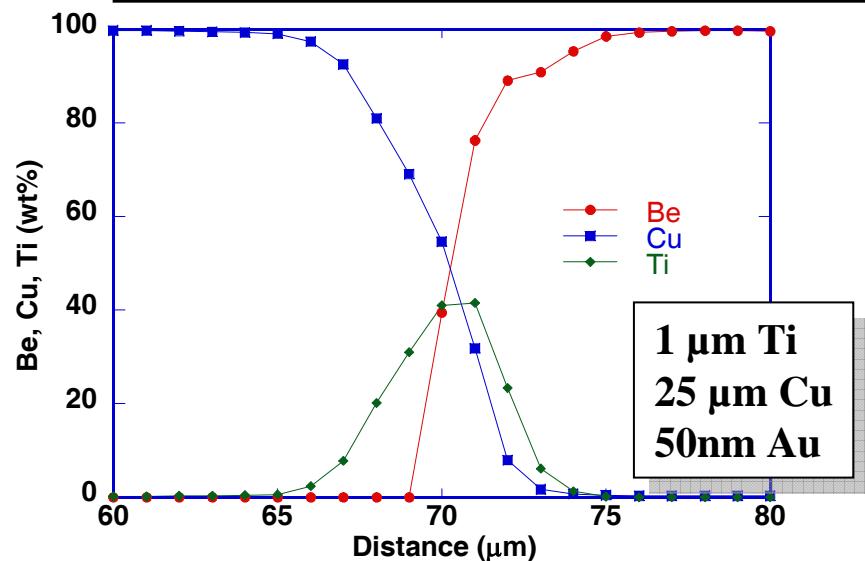
Metallography



- Specimens appear fully bonded – no obvious lack of bond defects
- Thickness of copper layer did not vary as expected (not 2x different)
 - “25 μm ” specimen much thicker than expected ~ 50 microns
 - “50 μm ” ~ 60 microns thick
 - PVD thickness incorrect, chrome diffusing???
- Titanium layer appears to be completely reacted for 1 micron



Electron Microprobe Traces of Interface

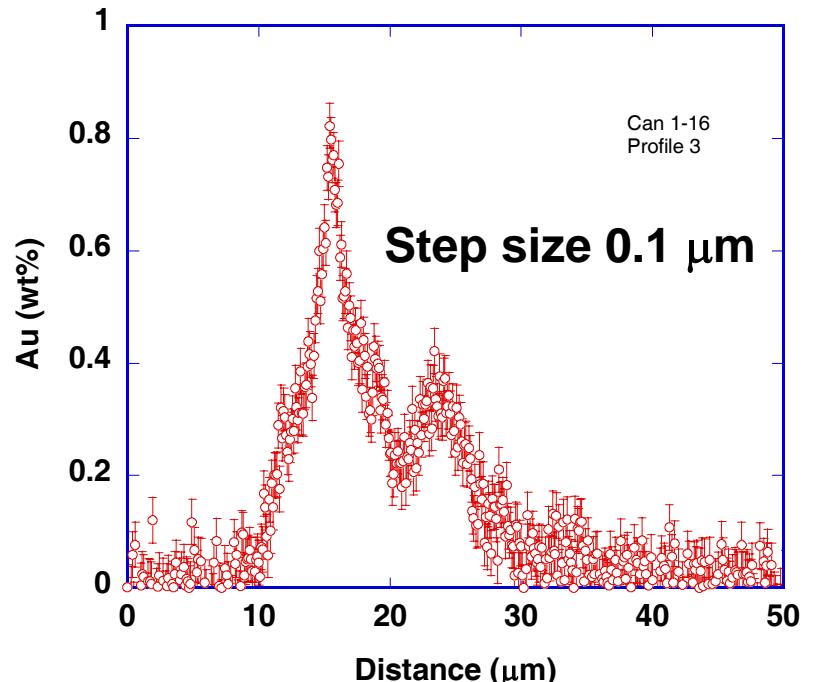
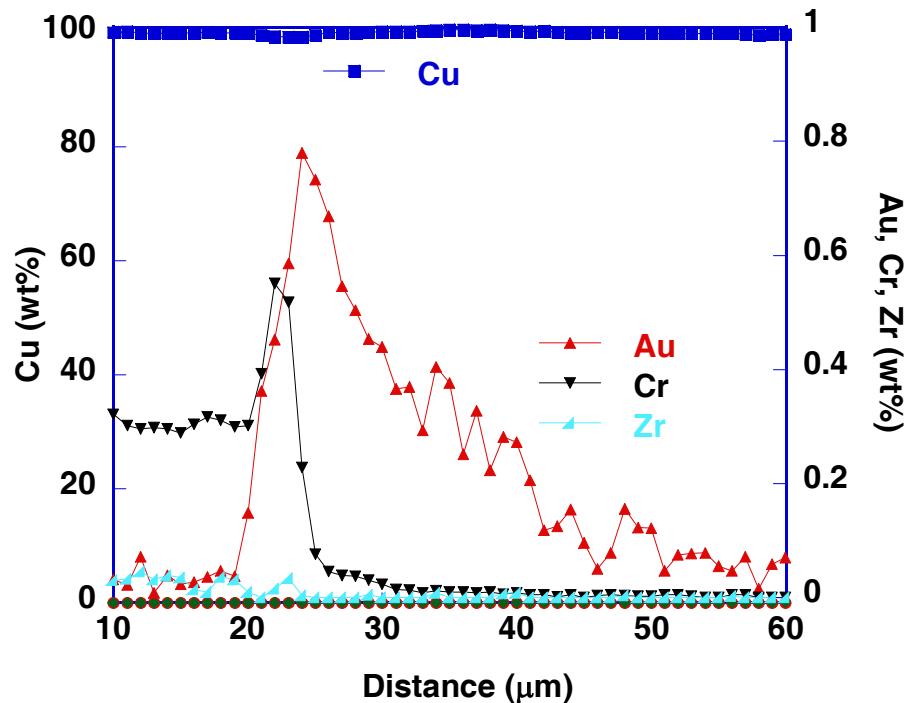


9/13/07, JDP 1822

- Backscattered images from the probe suggest that there may be multiple layers of interdiffusion
- Ti is effective in preventing copper and beryllium diffusion
- Insufficient resolution:
 - 1 micron is Ti
 - Intermetallic layers?



Gold Diffusion

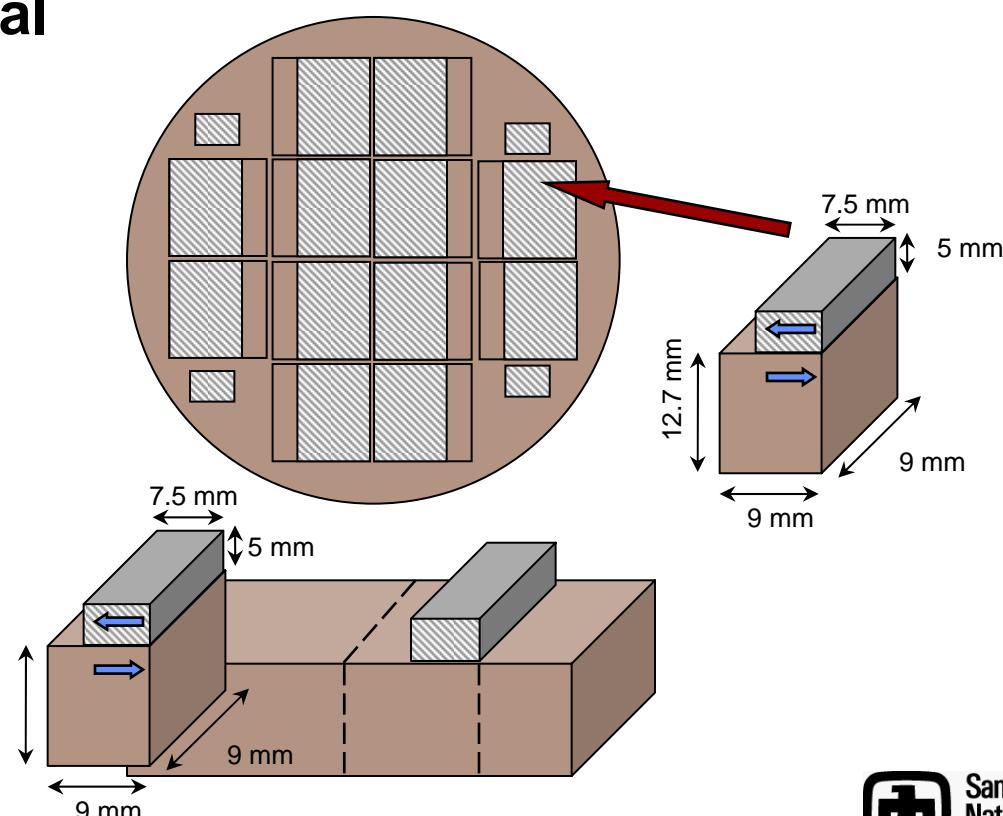
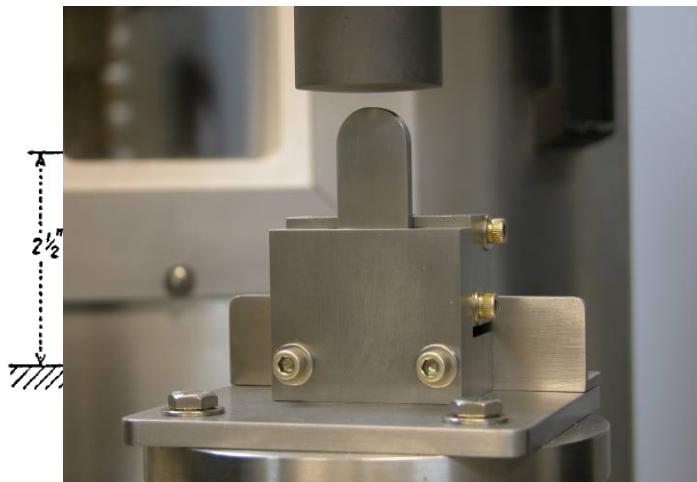


- Same generic profiles for all samples
- Gold profiles displayed significant variability, maximum peak value <1 wt%
- Starting thickness was 50nm, so actual peak concentration may be higher
- After bonding there is still a significant amount of gold at the interface
- Future work will minimize or eliminate the gold



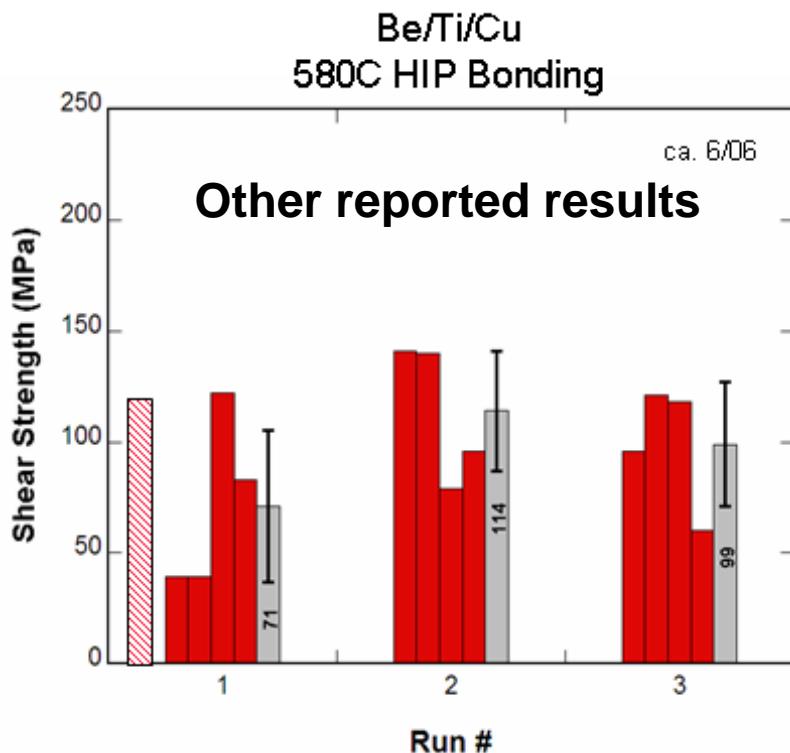
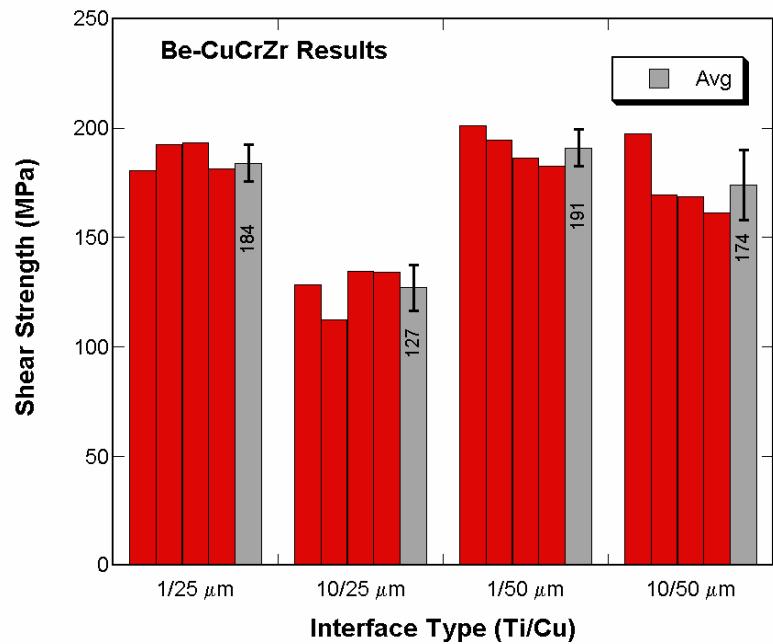
Shear Strength Testing

- **Shear coupons and metallographic specimens are extracted from bonded cylinders**
 - Modified ASTM A263/DIN 50162 shear tests
 - Conserves material





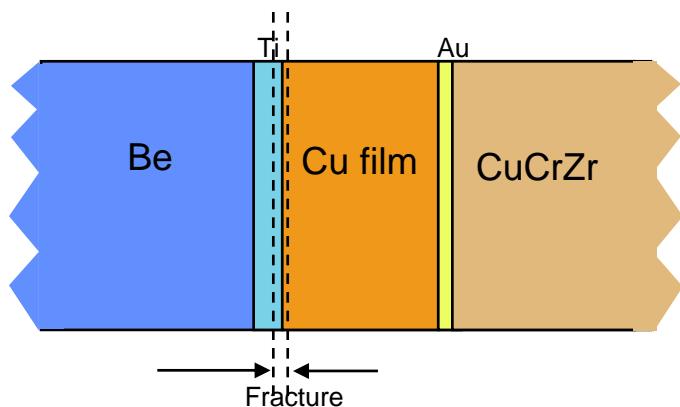
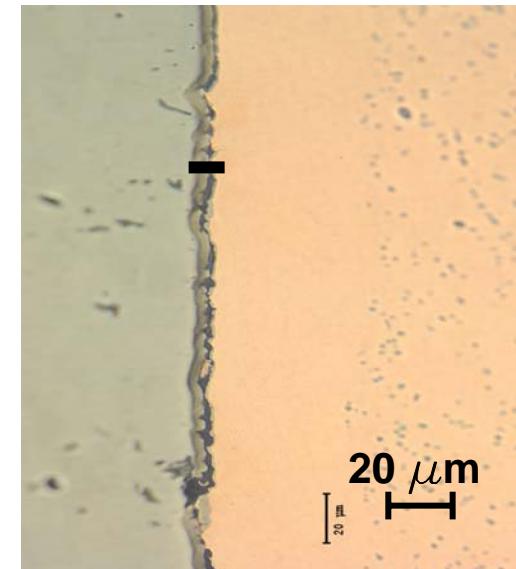
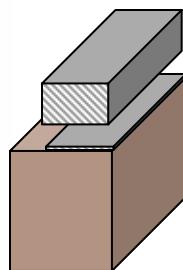
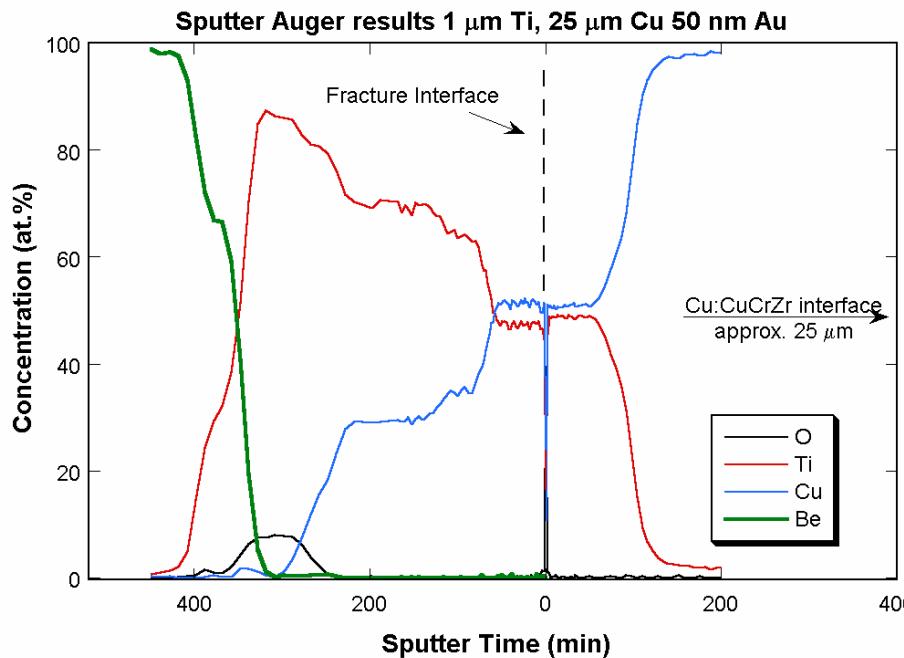
Shear Strength Testing Results



- Actual component requirements are for heat loads and cycles
 - No mechanical tests or requirements have been specified
- Shear samples were consistent within any group
- All results compared favorably with other reported results for similar testing



Auger depth profiling of fracture surface

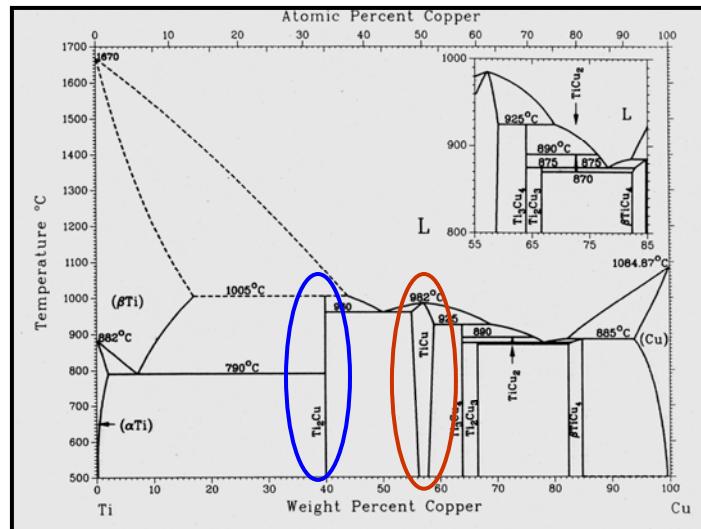
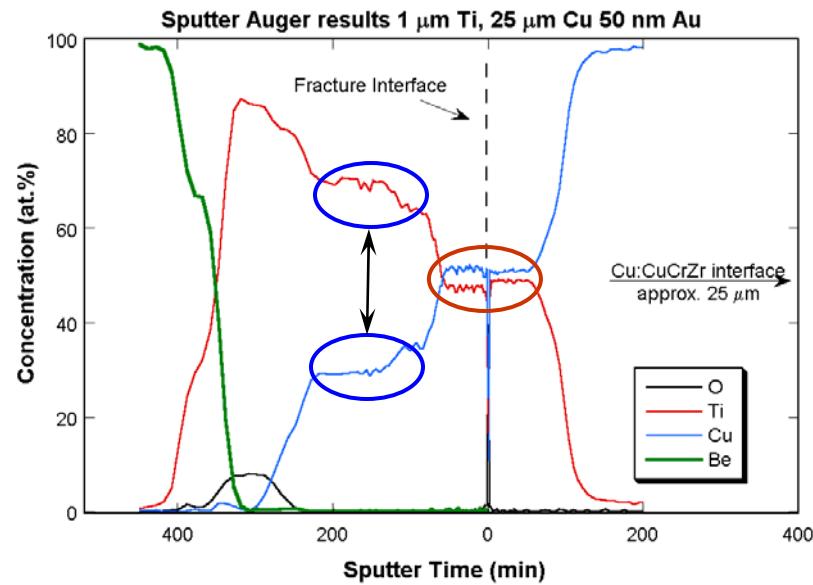


- 1 μm Ti metallization

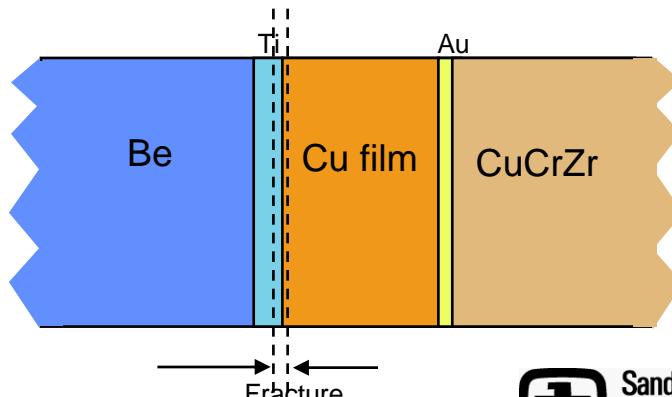
- Fracture is coincident with 50 at% Cu-50 at.% Ti that extends over some depth on either side of the fracture surface
- Cu penetration nearly to Be/Ti interface
 - Specify 2 μm Ti (min) metallizations for all future bonding studies



Auger Profiles/Intermetallic ID's



- Plateaus in Cu-Ti depth profiles correspond to specific intermetallic compounds identifiable in the Ti/Cu phase diagram
 - Ti_2Cu (η -phase)
 - TiCu (ζ -phase)
- No obvious Cu and Be interaction
- Same generic profiles for all 4 joint types





Conclusions

- Diffusion bonding using HIP produced favorable bonds
- Ti, Cu and Au interlayers were effective
- A minimum of 1 micron of Ti is necessary
- Gold can still be detected after bonding
- Two Cu/Ti intermetallics have been identified
- Relatively high shear strength values were measured
- Failure occurs in the TiCu intermetallic layer